 ch Notes

Application/Control No.	Applicant(s)/Patent ur Reexamination	nder
10/764,854	OKMIANSKI ET AL.	
Examiner	Art Unit	
David E. Martinez	2181	

SEARCHED				
Class	Subclass	Date	Examiner	
710	15,18,29,3 0,33- 35,52,57	4/21/2006	DM	
709	223-226	4/21/2006	DM	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY	
	DATE	EXMR
East see attached	4/21/2006	DM
Inventor Search eDan	4/21/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwent, IBM_TDB.	4/21/2006	DM